| Search Notes | | | | | |
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| Application No. | Applicant(s) |
|------------------|----------------|
| 09/255,856 | IWASAKI ET AL. |
| Examiner | Art Unit |
| Stephen W. Smoot | 2813 |

| SEARCHED | | | | |
|----------|----------|-----------|----------|--|
| Class | Subclass | Date | Examiner | |
| 257 | 751 | 5/17/2004 | sws | |
| 257 | 762 | 5/17/2004 | sws | |
| 257 | 767 | 5/17/2004 | sws | |
| 257 | 768 | 5/17/2004 | sws | |
| 438 | 627 | 5/17/2004 | sws | |
| 438 | 643 | 5/17/2004 | sws | |
| 438 | 653 | 5/17/2004 | sws | |
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| INTERFERENCE SEARCHED | | | | | |
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| Class | Subclass | Date | Examiner | | |
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| SEARCH NOTES (INCLUDING SEARCH STRATEGY) | | | | |
|--|-----------|---------------|--|--|
| | DATE | EXMR | | |
| Key Words: Interconnects - Copper, Platinum; Plug/Via - Ruthenium; | 5/17/2004 | L.D.S sws | | |
| Diffusion Barrier - Titanium Nitride, Ruthenium, Rhodium, Osmium, Iridium, Platinum; | 5/17/2004 | S.U.S sws | | |
| Electromigration; Primary Constituents. | 5/17/2004 | L.D.L. sws | | |
| | | | | |
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| Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB | 5/17/2004 | S.W.S. | | |
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